

given v_i is scheduled before all others

$$TF(v_i, l) = SF(v_i, l) + PF(v_m, l) + PF(v_n, l) + SF(v_j, l) + SF(v_k, l)$$

we don't consider already scheduled nodes

FD-MLRC is $O(n^2)$ as calculation of TF takes $O(n)$ time

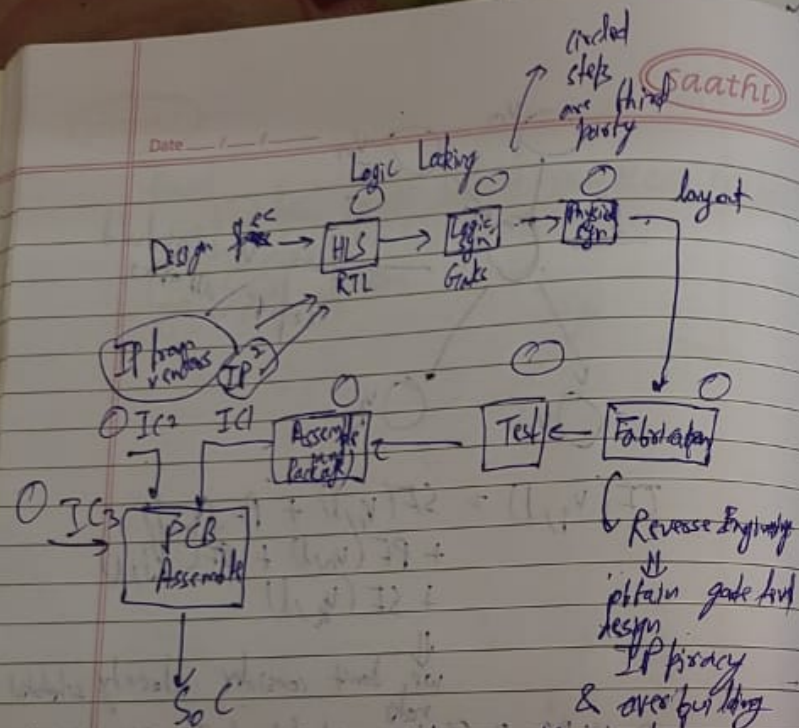
FD-MR-LC (a, λ) obj min

while (all op are scheduled)

- { compute the time frame (mobility)
- compute operation's type probability
- compute self force, pred/succ force
- Schedule the opn v_i with least total force in its time frame

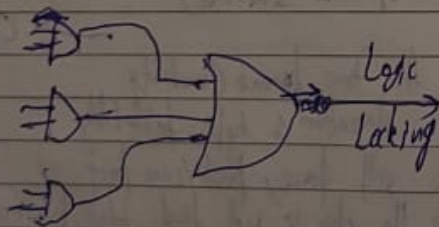
$\rightarrow O(n^3)$

Date _____

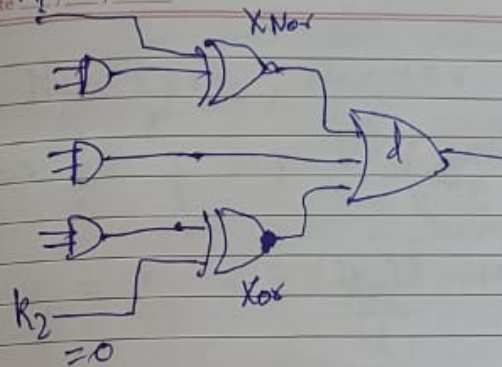


Hardware Trojan - Malicious Modification of design

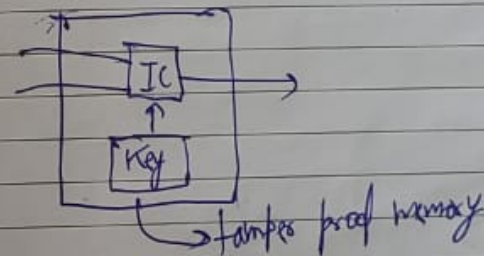
To prevent reverse engineering the sch is logic locking



Date $R_1 = 1$

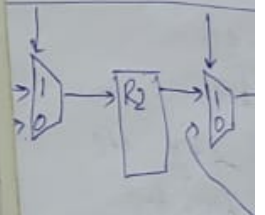


This circuit is equivalent to earlier only if $R_1 = 1 / R_2 = 0$



saathi

Attack - leaked design net
Hack - leaked design net
Attack - leaked design net
PG based attack
Synthesis based attack
Attack
Attack



Key

with Scan Enable

on the design set
with SE = 1 (we get
pattern from register)

MLRC

Objective is to increase concurrency to decrease latency

List MLRC (Gru)

while (any operation remains to be scheduled) {
for each resource R_i

U_i = candidate available in R_i

T_i = running operation in R_i

Calculate the total for all $U_i \in U_i$

Select $S_p \subset U_i$ s.t. $|T_i| + |S_p|$ is max
and TF maximized

Logic Locking

Different abstraction level

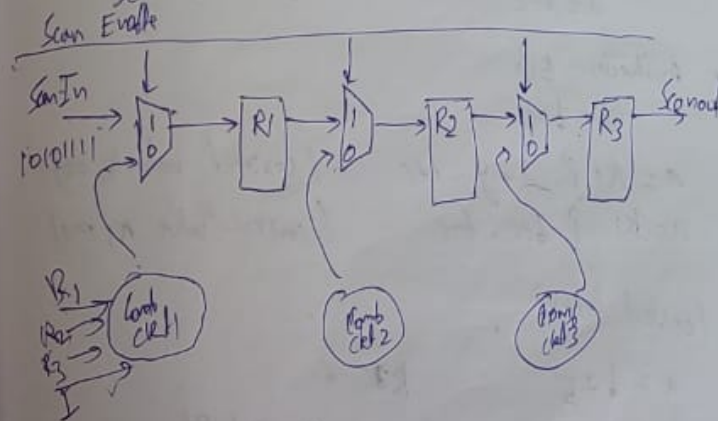
- C level
- RTL
- Gate Level

Threat Model

- Extract a gate level netlist from the layout by reverse engineering (locked design)
- Attacker has no info about the design (white box)
- Buy functional IP from market → can be used to verify the key

- Attack
 - Oracle guided attack - locked design netlist + oracle
 - Oracle less attack - locked design netlist
 - Functional Attack
 - SAT attack
 - ATPG based attack
 - Re-Synthesis based attack
 - Structural Attack
 - ML based Attack

Scan Chain Access



n -reg in scan chain

- Run n cycles with $\text{ScanEnable} = 1$ (This stores the input pattern in registers)
- one clk, run the design $\text{ScanEnable} = 0$ (we know the expected output for each register)
- Run n clk with $\text{SE} = 1$ (we get the output pattern from registers)

• ~~Conditional~~ C-level locking
Conditional Exp

if (c)
a = b + c ;
else a = b - c ;

↓
if (c ⊕ k₂)
a = b + c
else a = b - c

or

if (c ⊕ k₂)
a = b - c
else a = b + c

here k₂ = 1

• Arithmetic Exp

a = b + c

a = K₁ ? 2 * y : b + c (correct value K₁ = 0)

a = K₁ ? b + c : b - c (correct value K₁ = 1)

• Constant locking

a = b + 5

R = 6

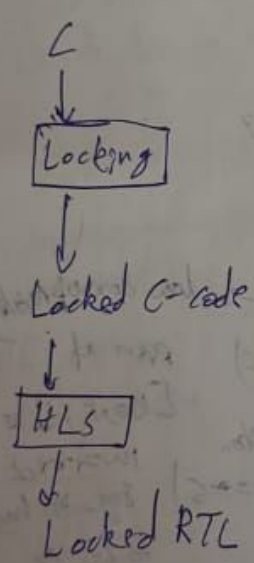
5 0 1 0 1
⊕ 6 0 1 1 0
—
 0 0 1 1

a = b + 3 ⊕ k

aktab
- rat

- Logic locking
- Behavioral level $\xrightarrow{\text{H-LOCK}}$ C-level $\xrightarrow{\text{during HLS}}$ } 2 levels at which locking can be done at behavioral level
 - RTL $\xrightarrow{\text{TAO}}$ ASSUME
HOST
Dishonest Oracle
 - Gate level
 - 3 types of locking in general {
 - constant
 - operation
 - condition
- highly complex
if key not known operation lost
semantic info

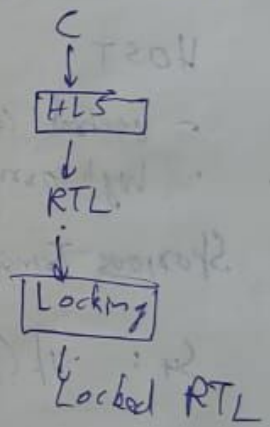
H-LOCK



TAO



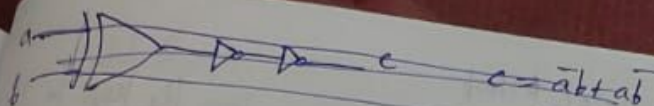
ASSURE, HOST



- Advantage of Locking at higher level \Rightarrow we have semantic info that can be used

Comparison:

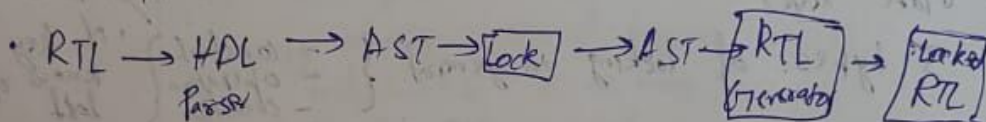
- | | |
|--|---|
| <p>H-LOCK</p> <ul style="list-style-type: none"> Easy to implement HLS independent (not dependent on software) | <p>TAO</p> <ul style="list-style-type: none"> harder to implement less overhead |
|--|---|



The drawback of RTL is that RL circuit needs to be present always for increment. The output of even for increment is $abtab$.

- TAO can avoid overhead since it can resampling the operations in case of a false key as it can simply borrow output from existing circuit on the other hand in H-LOCK - extra computation needed to be present always ($k+1? b+c: b-c$) causing overhead.

ASSURE / HOST



ASSURE {
- constant
- operation
- pointer

HOST

- control corruptibility \rightarrow low corruptibility
- high corruptibility \rightarrow corrupt control

Spurious Transition in controller.

S_4 : if $([k_0, k_1] = 26'00 \wedge reg_01 = 10)$ even if $[k_0, k_1]$ is incorrect reg_01 has to be 10 for spurious transition
 $next_state = S8$ spurious transition
 else if $([k_0, k_1] = 26'01 \wedge reg_02 = 05)$ reg_02 has to be 05 for spurious transition
 $next_state = S9$
 else $next_state = S5$ original transition

can avoid overhead since it is not scrambling the data

Gate level logic locking
Combinational Part

→ Pre SAT Era - RLL, FLL, SLL

→ SAT Attack

→ Post-SAT - SarcLock, Anti-SAT, Cycle-SAT, SFLY
Provably Secure Dishonest Oracle Delay

Lock, Clocklocking

Locks combinational part

Sequential Part

→ Locking the FSM Post Harpoon

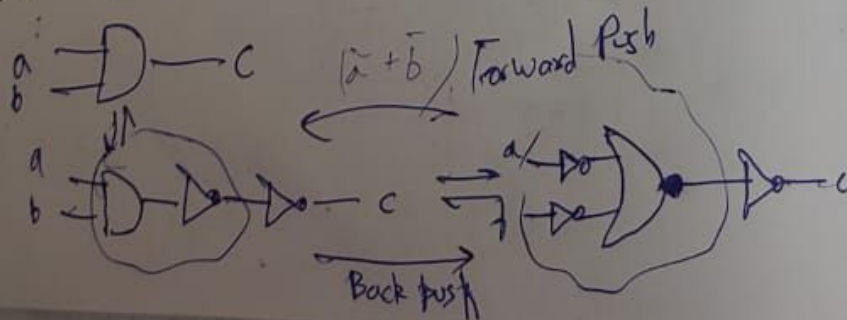
→ Lock the datapath regs Scanlock

Random Logic Locking

XOR/XNOR based key insertion at random location

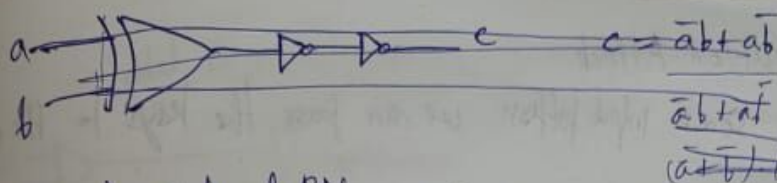
Key easily identified for XOR = 0 and for XNOR = 1

Soln - Bubble Pushing



Tamper
proof
circuit

Combinational Logic Locking



The drawback of RLL is that RLL circuit may produce correct output even for incorrect key values for many of the inputs. Low Output Corruptibility.

Fault Analysis based Logic Locking (FLL)

Based on analysis we put XOR, XNOR instead of randomly to ensure that output corruptibility is high.

Physical Fault { stuck at zero
stuck at one

$$FI_n \text{ (Fault impact of } n) \\ = (P_0 \times C_0) + (P_1 \times C_1)$$

VLSI Testing for physical flaws in the circuit

VLSI Testing of Logic Locking

Simulation
Fault pool
Multiple fault

$$OC = \frac{1}{PQM} \sum_{i=1}^P \sum_{j=1}^Q HD(O_F(I_i), O_L(I_i, K_j)) \times 100\%$$

P random input patterns
Q random key values
L Locked Netlist
M-bit output



avoid overhead since it ~~and~~ resampling the ~~operations~~
of a fake key as it can simply borrow other

Sensitization Attack

For some input pattern we can pass the keys to the effect

SLL

Inserts keys to maximize interdependence by increasing
degree size

SAT Attack

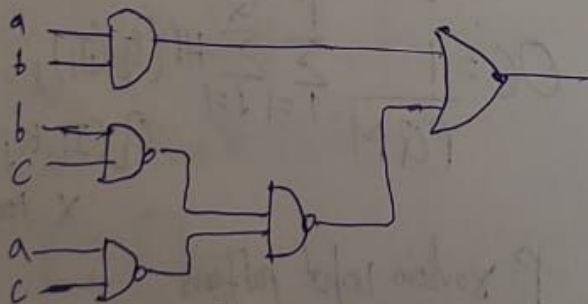
Satisfiability Problem - Given a formula f is there
an input for which it becomes TRUE

Boolean Formula: $(a \wedge b) \wedge (a' \wedge b')$ unsatisfiable

↓
SAT solver

Integer Domain: $x + y > 10$

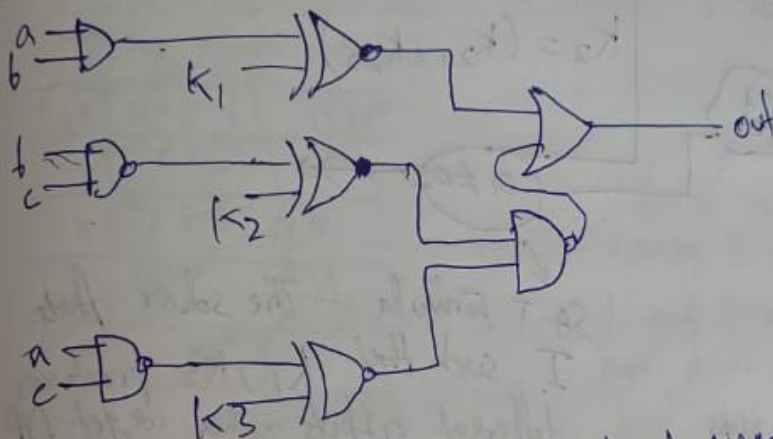
↓
SMT solver



Combinational Logic Liking

Time taken: 1 CAT 11/12

Locked Design



For design we can solve this formula

$$out = OR(XNOR(AND(a, K_1), NAND(XOR(NAND(b, K_2), XNOR(NAND(c, K_3))$$

if (c)

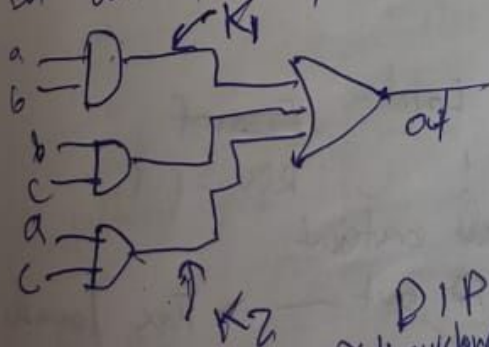
$$a = x + y \Leftrightarrow a = (if\ c, x + y, x - y)$$

else

$$a = x - y$$

if - else

But what to do for C code

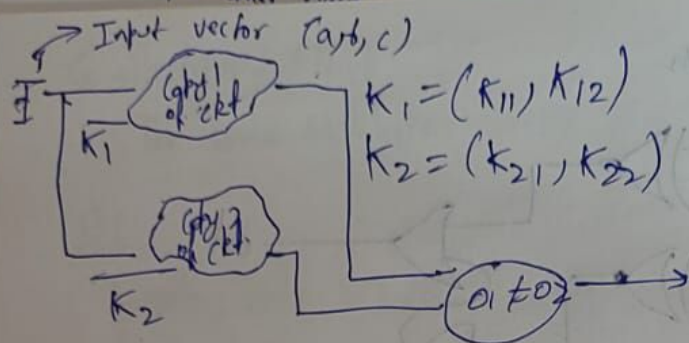


Not good
does not narrow
down keys

DIP
Distinguishing Input
Pattern identifies atleast one wrong key

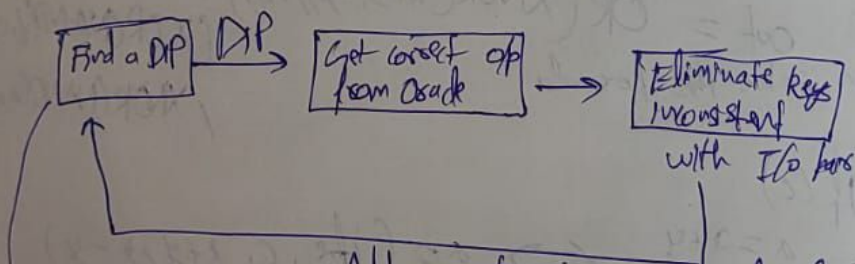
if $I = K$ invert the output
if $I \neq K$ keep output as it

can avoid overhead since it avoids recompiling the formulas of a false key as it can simply borrow other output on the other hand



SAT Formula - The solver finds I such that K_1, K_2 produces different outputs. Thus we get DIP

SAT ~~is~~ Steps



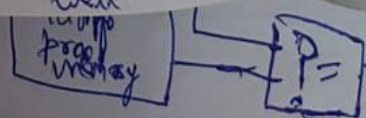
once NO DIP
 Run solver for formula $O_1 = O_2$
 to get one of the possible correct key

Add constraint to SAT formula corresponding to wrong key

a	b	c	Actual Label	Expected
0	0	0	01	key = 11

So add constraint
 $1 = \text{out}$
 $a=0, b=0, c=0$

This formula eliminates other keys for wrong key (0010) is well



Combinational Logic

Time taken by SAT Mode

$$T = \sum_{i=1}^n A_i$$

$$\lambda = \# \text{ iterations} = \# \text{ DR}$$

t_1 = time taken by SAT solvers to get DIP;

Either increase λ or β to thrust AT value

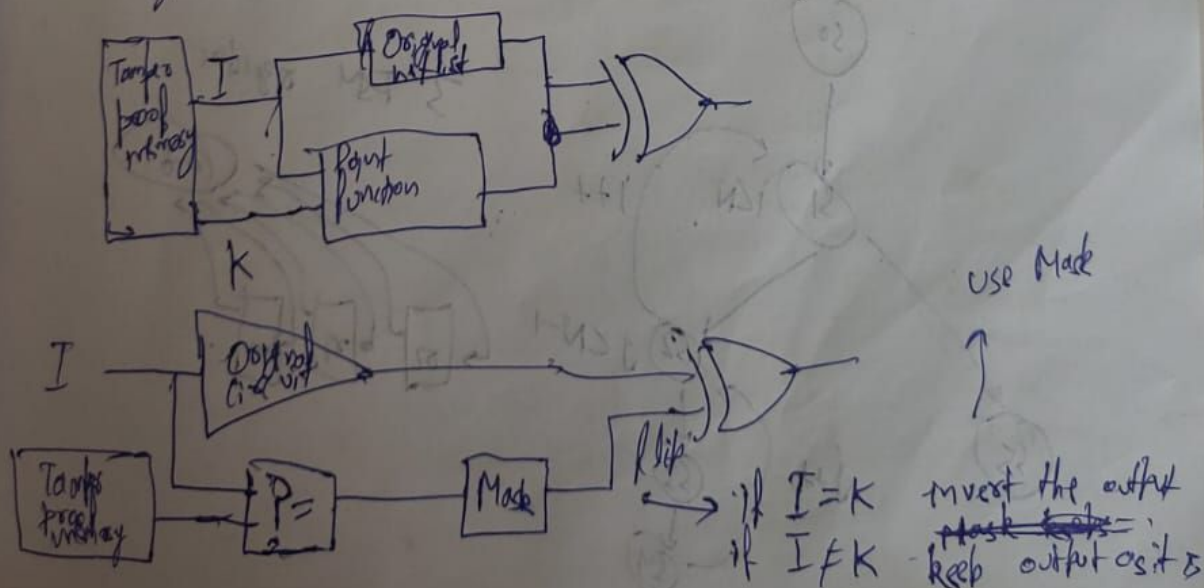
Strong DIP - channels large number of insect eggs

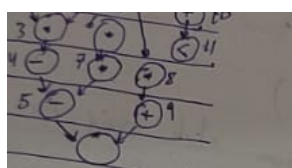
Weak DIP - small

If we ensure that we get only weak DIP we can increase \downarrow
we do this by modifying circuit

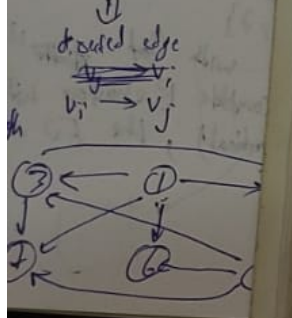
Each Input partitions keys into correct/increased based on corresponding output. If we ensure this partition is skewed for each input then number of keys eliminated is very less.

SARLOCK (SAT Attack Resistant Logic Locking)
Modify design so that it generates weak DIFs





Segn graph
 Compatibility Graph (For
 $G = (V, E)$, $V =$
 $E = (v_i, v_j)$ if s_i
 not v_j
 v_i, v_j are not a
 $A_j \geq s_i + d_i$ or



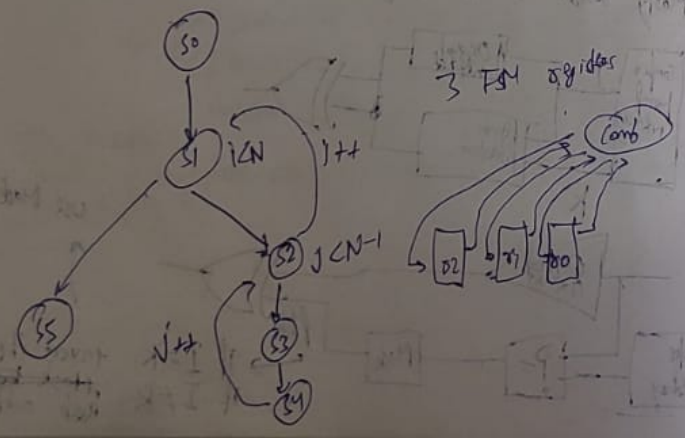
ANTISAT (In ANTISAT ~~we have~~ ~~the~~ ~~is~~ ~~changed~~)
 AND Tree
 Cycle SAT \rightarrow Prevents SAT from working in scan 1 iteration

The problem with SARLOCK, ANTISAT, AND TREE is low output
 consistency this ~~is~~ locked circuit gives almost correct output
 and ~~is~~ susceptible to structural attacks because
 these are

SARLOCK, ANTISAT is susceptible to structural attack
 since original circuit is left unbroken

SFLL-HD (original circuit is also modified to create
 Functionality Stuffed Circuit FSC)

Sequential Locking
 Registers/FF
 Data path registers \rightarrow usually connected in scan chain
 FSM registers \rightarrow "not connected" "no"



For logic heavy outputs
 we have create, locked outputs and their scan chain

If we lock scan chain we can't get internal values for
 each input/output thus we can't apply SAT attack to a
 subpart

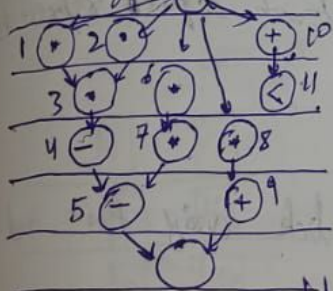
FSM Locking \rightarrow ~~Not~~ Unbroken

Identify ~~the~~ controls FSM in design
 Add a 'authentication' block
 Add a dummy FSM
 The ~~the~~ start state of original FSM results only for
 a correct sequence of inputs which are as long otherwise
 it means to dummy start state

Lock Scan Chain of registers
 Lock Scan Chain of blocks

Resource Allocation & Binding

Two methods to solve
 → FU Allocation and Binding
 → Reg. Allocation and Binding



Seq. graph

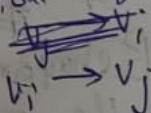
Compatibility Graph (For each type of graph)

$G = (V, E)$, $V = \{v_i/v_j\}$ is a node in sequence graph, i.e., $1, \dots, n$

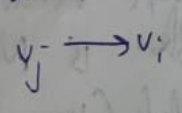
$E = (v_i, v_j)$ if schedule of v_i and v_j are not overlapping

v_i, v_j are not overlapping
 if $f_j \geq f_i + d_i$ or $f_i \geq f_j + d_j$

↓
 directed edge

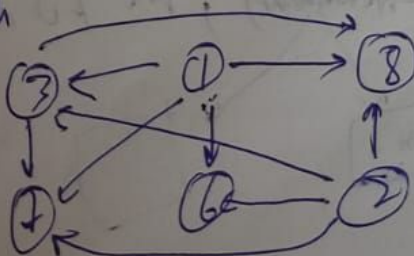


↓
 directed edge



Compatibility graph

for Mult



Conflict Graph

$K(G)$ → Maximum nodes having same color

(The part before this is done in another notebook and before that is in this notebook)

1 and 2 must map to different FU as they are running in parallel.

1 and 3 can map to same FU as they ~~are~~ don't run in parallel

don't run in parallel

Compatibility Graph

$K(G) \rightarrow M$

$K(G) \rightarrow$

perfect G

$G) = X$

$G) =$

de ha

ch

perfect

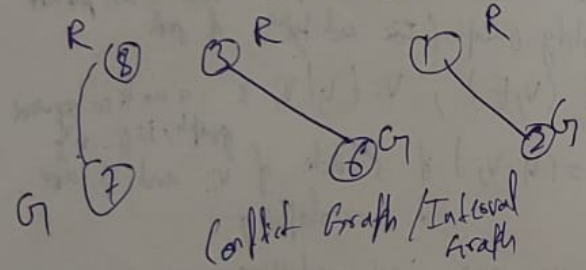
up

Chique cover problem

Identify min disjoint cliques that cover all the nodes of compatibility graph. Each clique represents one FU

$$\#FU = K(G(V, E))$$

Identify the maximum clique every time and remove corresponding edges



$$FU_R = \{1, 3, 4\}$$

$$FU_G = \{2, 6, 7\}$$

For generic behaviour with ~~loop~~ if-else, in all the problem is NP-complete. Behaviour with only single basic block (non-hierarchical), the FU alloc and is polynomially solvable.

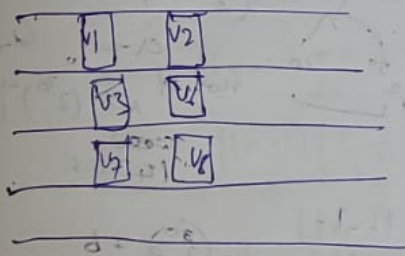
Left Edge Algorithm



Conflict Graph, Interval Graph

Every Interval Graph is Conflict Graph but not the other way around.

Can be mapped to intervals

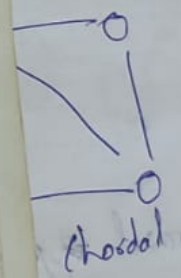


$K(G) \rightarrow$ clique cover # minimum to cover

$$\chi(G) = K(G)$$

$$K(G) = \chi(G)$$

de having mo



Conflict Graph

in osim

\Rightarrow